

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE

INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE  
COMITÉ INTERNATIONAL SPÉCIAL DES PERTURBATIONS RADIOÉLECTRIQUES

AMENDMENT 1  
AMENDEMENT 1

**iTeh STANDARD PREVIEW**  
**(standards.iteh.ai)**

**Specification for radio disturbance and immunity measuring apparatus and methods –**

[CISPR 16-1-3:2004/AMD1:2016](https://standards.iteh.ai/en/standards/cispr-16-1-3-2004-amd1-2016)

**Part 1-3: Radio disturbance and immunity measuring apparatus – Ancillary equipment – Disturbance power**

<https://standards.iteh.ai/en/standards/cispr-16-1-3-2004-amd1-2016>  
[1ae5ff102e8/cispr-16-1-3-2004-amd1-2016](https://standards.iteh.ai/en/standards/cispr-16-1-3-2004-amd1-2016)

**Spécifications des méthodes et des appareils de mesure des perturbations radioélectriques et de l'immunité aux perturbations radioélectriques –  
Partie 1-3: Appareils de mesure des perturbations radioélectriques et de l'immunité aux perturbations radioélectriques – Matériels auxiliaires – Puissance perturbatrice**



## THIS PUBLICATION IS COPYRIGHT PROTECTED

Copyright © 2016 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester. If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

Droits de reproduction réservés. Sauf indication contraire, aucune partie de cette publication ne peut être reproduite ni utilisée sous quelque forme que ce soit et par aucun procédé, électronique ou mécanique, y compris la photocopie et les microfilms, sans l'accord écrit de l'IEC ou du Comité national de l'IEC du pays du demandeur. Si vous avez des questions sur le copyright de l'IEC ou si vous désirez obtenir des droits supplémentaires sur cette publication, utilisez les coordonnées ci-après ou contactez le Comité national de l'IEC de votre pays de résidence.

IEC Central Office  
3, rue de Varembe  
CH-1211 Geneva 20  
Switzerland

Tel.: +41 22 919 02 11  
Fax: +41 22 919 03 00  
[info@iec.ch](mailto:info@iec.ch)  
[www.iec.ch](http://www.iec.ch)

### About the IEC

The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

### About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigenda or an amendment might have been published.

#### IEC Catalogue - [webstore.iec.ch/catalogue](http://webstore.iec.ch/catalogue)

The stand-alone application for consulting the entire bibliographical information on IEC International Standards, Technical Specifications, Technical Reports and other documents. Available for PC, Mac OS, Android Tablets and iPad.

#### IEC publications search - [www.iec.ch/searchpub](http://www.iec.ch/searchpub)

The advanced search enables to find IEC publications by a variety of criteria (reference number, text, technical committee,...). It also gives information on projects, replaced and withdrawn publications.

#### IEC Just Published - [webstore.iec.ch/justpublished](http://webstore.iec.ch/justpublished)

Stay up to date on all new IEC publications. Just Published details all new publications released. Available online and also once a month by email.

#### Electropedia - [www.electropedia.org](http://www.electropedia.org)

The world's leading online dictionary of electronic and electrical terms containing 20 000 terms and definitions in English and French, with equivalent terms in 15 additional languages. Also known as the International Electrotechnical Vocabulary (IEV) online.

#### IEC Glossary - [std.iec.ch/glossary](http://std.iec.ch/glossary)

65 000 electrotechnical terminology entries in English and French extracted from the Terms and Definitions clause of IEC publications issued since 2002. Some entries have been collected from earlier publications of IEC TC 37, 77, 86 and CISPR.

#### IEC Customer Service Centre - [webstore.iec.ch/csc](http://webstore.iec.ch/csc)

If you wish to give us your feedback on this publication or need further assistance, please contact the Customer Service Centre: [csc@iec.ch](mailto:csc@iec.ch).

### A propos de l'IEC

La Commission Electrotechnique Internationale (IEC) est la première organisation mondiale qui élabore et publie des Normes internationales pour tout ce qui a trait à l'électricité, à l'électronique et aux technologies apparentées.

### A propos des publications IEC

Le contenu technique des publications IEC est constamment revu. Veuillez vous assurer que vous possédez l'édition la plus récente, un corrigendum ou amendement peut avoir été publié.

#### Catalogue IEC - [webstore.iec.ch/catalogue](http://webstore.iec.ch/catalogue)

Application autonome pour consulter tous les renseignements bibliographiques sur les Normes internationales, Spécifications techniques, Rapports techniques et autres documents de l'IEC. Disponible pour PC, Mac OS, tablettes Android et iPad.

#### Recherche de publications IEC - [www.iec.ch/searchpub](http://www.iec.ch/searchpub)

La recherche avancée permet de trouver des publications IEC en utilisant différents critères (numéro de référence, texte, comité d'études,...). Elle donne aussi des informations sur les projets et les publications remplacées ou retirées.

#### IEC Just Published - [webstore.iec.ch/justpublished](http://webstore.iec.ch/justpublished)

Restez informé sur les nouvelles publications IEC. Just Published détaille les nouvelles publications parues. Disponible en ligne et aussi une fois par mois par email.

#### Electropedia - [www.electropedia.org](http://www.electropedia.org)

Le premier dictionnaire en ligne de termes électroniques et électriques. Il contient 20 000 termes et définitions en anglais et en français, ainsi que les termes équivalents dans 15 langues additionnelles. Egalement appelé Vocabulaire Electrotechnique International (IEV) en ligne.

#### Glossaire IEC - [std.iec.ch/glossary](http://std.iec.ch/glossary)

65 000 entrées terminologiques électrotechniques, en anglais et en français, extraites des articles Termes et Définitions des publications IEC parues depuis 2002. Plus certaines entrées antérieures extraites des publications des CE 37, 77, 86 et CISPR de l'IEC.

#### Service Clients - [webstore.iec.ch/csc](http://webstore.iec.ch/csc)

Si vous désirez nous donner des commentaires sur cette publication ou si vous avez des questions contactez-nous: [csc@iec.ch](mailto:csc@iec.ch).

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE

INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE  
COMITÉ INTERNATIONAL SPÉCIAL DES PERTURBATIONS RADIOÉLECTRIQUES

AMENDMENT 1 **iTeh STANDARD PREVIEW**  
AMENDEMENT 1 **(standards.iteh.ai)**

**Specification for radio disturbance and immunity measuring apparatus and methods –**

[CISPR 16-1-3:2004/AMD1:2016](https://standards.iteh.ai/catalog/standards/sist/5c18d183-e3cc-4eb3-961a-1ac15fd02e8/cispr-16-1-3-2004-amd1-2016)

**Part 1-3: Radio disturbance and immunity measuring apparatus – Ancillary equipment – Disturbance power**

**Spécifications des méthodes et des appareils de mesure des perturbations radioélectriques et de l'immunité aux perturbations radioélectriques –  
Partie 1-3: Appareils de mesure des perturbations radioélectriques et de l'immunité aux perturbations radioélectriques – Matériels auxiliaires – Puissance perturbatrice**

INTERNATIONAL  
ELECTROTECHNICAL  
COMMISSION

COMMISSION  
ELECTROTECHNIQUE  
INTERNATIONALE

ICS 33.100.10, 33.100.20

ISBN 978-2-8322-3244-6

**Warning! Make sure that you obtained this publication from an authorized distributor.  
Attention! Veuillez vous assurer que vous avez obtenu cette publication via un distributeur agréé.**

## FOREWORD

This amendment has been prepared by CISPR subcommittee A: Radio-interference measurements and statistical methods, of IEC technical committee CISPR: International special committee on radio interference.

The text of this amendment is based on the following documents:

CDV	Report on voting
CIS/A/1111/CDV	CIS/A/1138/RVC

Full information on the voting for the approval of this amendment can be found in the report on voting indicated in the above table.

The committee has decided that the contents of this amendment and the base publication will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

**ITeH STANDARD PREVIEW**  
**(standards.iteh.ai)**

[CISPR 16-1-3:2004/AMD1:2016](https://standards.iteh.ai/catalog/standards/sist/5c18d183-e3cc-4eb3-961a-1ae5ffd02e8/cispr-16-1-3-2004-amd1-2016)

<https://standards.iteh.ai/catalog/standards/sist/5c18d183-e3cc-4eb3-961a-1ae5ffd02e8/cispr-16-1-3-2004-amd1-2016>

### 3.2 Abbreviations

*Delete, from the existing list, the abbreviation "RTF" and associated term "Reference transfer factor".*

### 4.3 The absorbing clamp assembly calibration methods and their relations

*Replace, in the existing second paragraph, the two occurrences of the word "three" by the word "two".*

*Replace, in the last sentence of the existing fourth paragraph, the word "three" by the word "two".*

*Delete the entire item c) (entitled "The reference device method") and all corresponding text, including Equations (9) and (10).*

*Replace, in the paragraph immediately following the existing item c), the two occurrences of the word "three" by the word "two".*

*Delete, in the fourth paragraph following the existing item c), the last sentence "Similarly, the reference transfer factor RTF is determined by" and corresponding Equation (12).*

*Delete the entire paragraph immediately following Equation (12).*

*Replace, in the last paragraph of this subclause, the second sentence by the following new sentence:*

[CISPR 16-1-3:2004/AMD1:2016](https://standards.iteh.ai/catalog/standards/sist/5c18d183-e3cc-4eb3-961a-f4jig-f4d02c0/cispr-16-1-3-2004-amd1-2016)

<https://standards.iteh.ai/catalog/standards/sist/5c18d183-e3cc-4eb3-961a-f4jig-f4d02c0/cispr-16-1-3-2004-amd1-2016>

The jig method gives the  $CF_{jig}$  from which the original absorbing clamp factor can be calculated using Equation (11).

*Add, at the end of this subclause, the following new paragraph:*

Absorbing clamps with different geometries, different arrangement and material of ferrites, different current probes as well as different housing material do require a separate determination of the JTF. A new determination is also required if a different type of jig is used, e.g. larger geometry.

#### 4.5.3 Requirements for the ACTS

*Add, after the first sentence of item e), the following new text:*

It is also permissible to use clamp factors provided on a calibration certificate by a calibration laboratory. However, such clamp factors that are used as a reference for an ACTS validation shall be determined only using the original calibration method.

#### 4.6.1 Overview

*Delete, in the second paragraph, the phrases "and the reference device calibration method" as well as "and the reference device clamp factor".*

**Figure 1 – Overview of the absorbing clamp measurement method and the associated calibration and validation procedures**

*In the figure, delete the entire item d).*

**Table 1 – Overview of the characteristics of the three-clamp calibration methods and their relation**

*In the title, replace the phrase “three-clamp” by the new phrase “two clamp”.*

*In the table, delete the entire third row (the row having the name “The reference device method”).*

**Figure 3 – Schematic overview of the clamp calibration methods**

*Delete Figure 3d.*

*Delete, from the key in this figure, the symbol “ $CF_{ref}$ ”*

*In the note, delete “and 3d”, and replace the word “three” by the new word “two”.*

iTeh STANDARD PREVIEW

**B.2 Calibration methods of the absorbing clamp assembly**

*Replace, in the first sentence of the first paragraph, the words “For all three” by the new word “Both”.*

<https://standards.iteh.ai/catalog/standards/sist/5c18d183-e3cc-4eb3-961a-1ae5ffd02e8/cispr-16-1-3-2004-amd1-2016>

**B.2.1.1 Calibration set-up and equipment**

*Replace, in the first sentence of the second dashed item, the phrase “larger than” by the new word “of”.*

*Add, after the second sentence of the third dashed point, the following new sentence:*

For practical reasons it is recommended to use a flexible lead under test.

*Add, after the dashed list, the following new note:*

NOTE A good match with the requirement of 4 mm diameter can be achieved by using the outer screen of a coaxial cable (for example RG-58).

**B.2.1.2 Calibration procedure**

*Add, after the second sentence of the third paragraph, the following new third sentence:*

The receiver cable shall be suspended such that it is always spaced at a minimum of 200 mm from the horizontal ground plane throughout the entire calibration process.

### B.2.2.2 Calibration procedure

Add, after the last sentence of the fourth paragraph, the following new sentence:

The receiver cable shall be treated with a SAD. The SAD shall be positioned as shown in Figures B.3 and B.4.

### B.2.3 The reference device calibration method

Delete this entire subclause.

### B.2.4 Measurement uncertainty of the absorbing clamp calibration

Add, immediately after the second bulleted list (pertaining to the jig calibration method) the following new note:

NOTE It is assumed that the measurement instrumentation uncertainty of the required correlation process with the original calibration method is sufficiently small such that there is no appreciable contribution to the uncertainty of the jig calibration method.

Delete the entire third dashed list (“The reference device calibration method”).

Replace the last paragraph of this subclause by the following new paragraph:

Detailed guidance on the treatment of the measurement instrumentation uncertainty for disturbance power measurements is given in CISPR 16-4-2.

### Figure B.3 – Side view of the calibration jig

Replace the existing Figure B.3 by the following new figure:

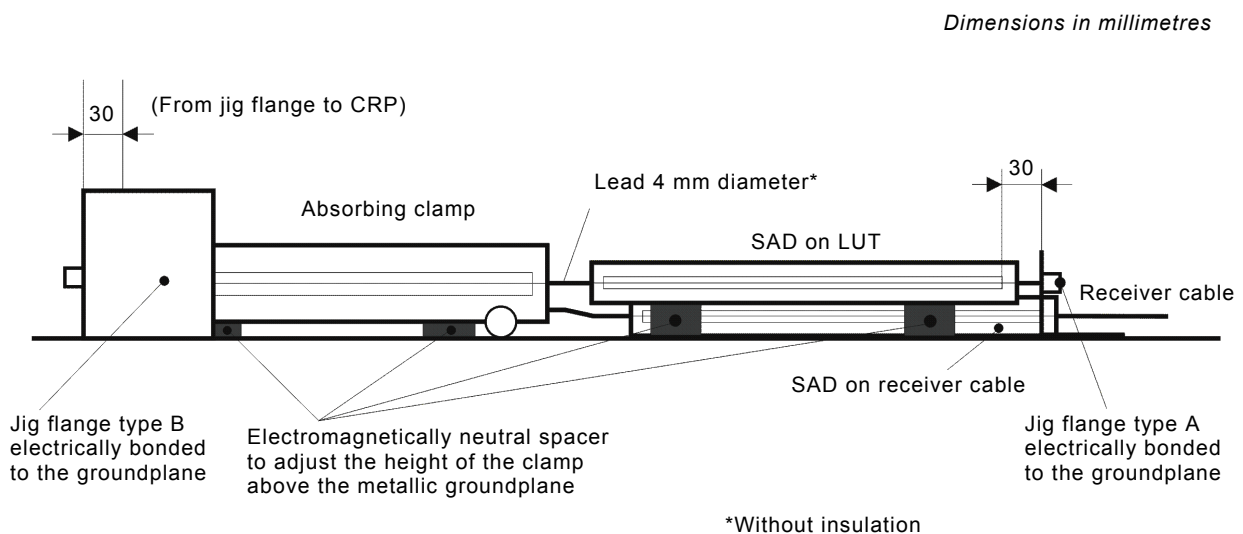
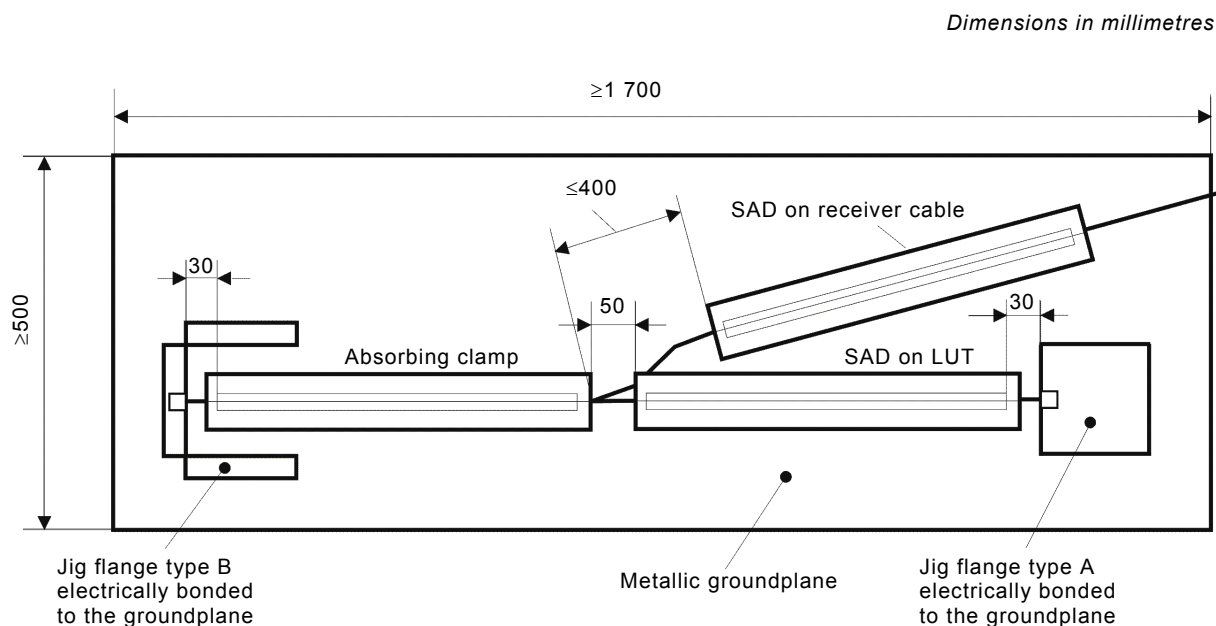


Figure B.3 – Side view of the calibration jig

**Figure B.4 – Top view of the jig**

Replace the existing Figure B.4 by the following new figure:



**iTeh STANDARD PREVIEW**  
(standards.iteh.ai)

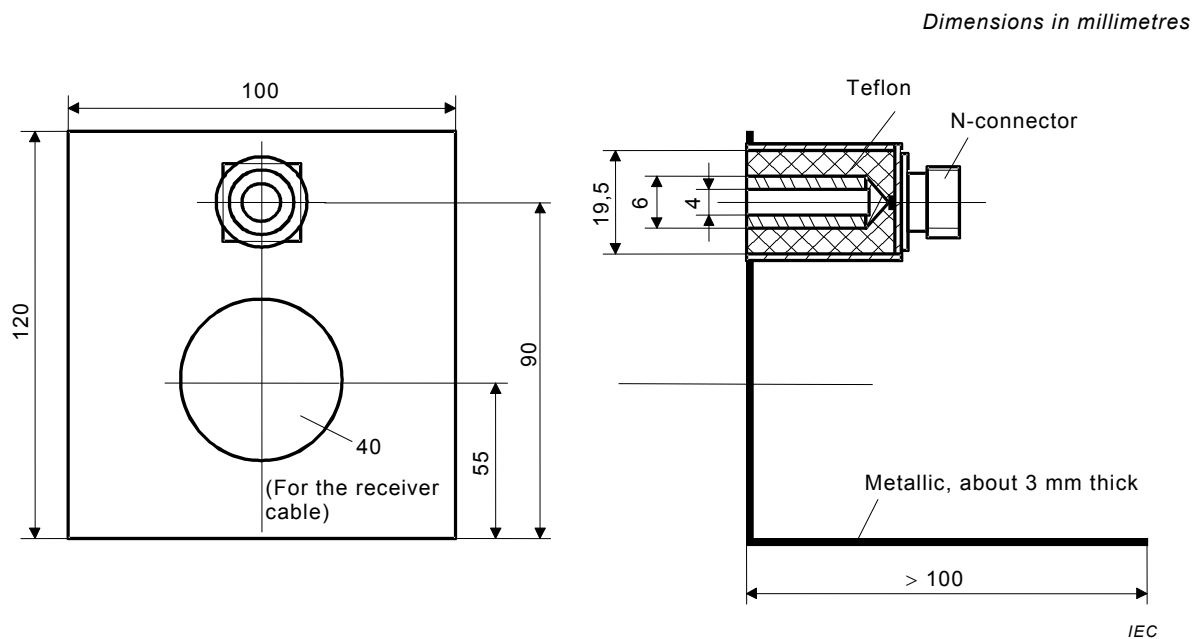
IEC

**Figure B.4 – Top view of the jig**

**Figure B.5 – View of the jigs vertical flange**

CISPR 16-1-3:2004/AMD1:2016  
<https://standards.iteh.ai/catalog/standards/sist/5c18d183-e3cc-4eb3-961a-3a5ff102e8/cispr-16-1-3-2004-amd1-2016>

Replace the existing Figure B.5 by the following new Figure B.5, consisting of Figures B.5a and B.5b:

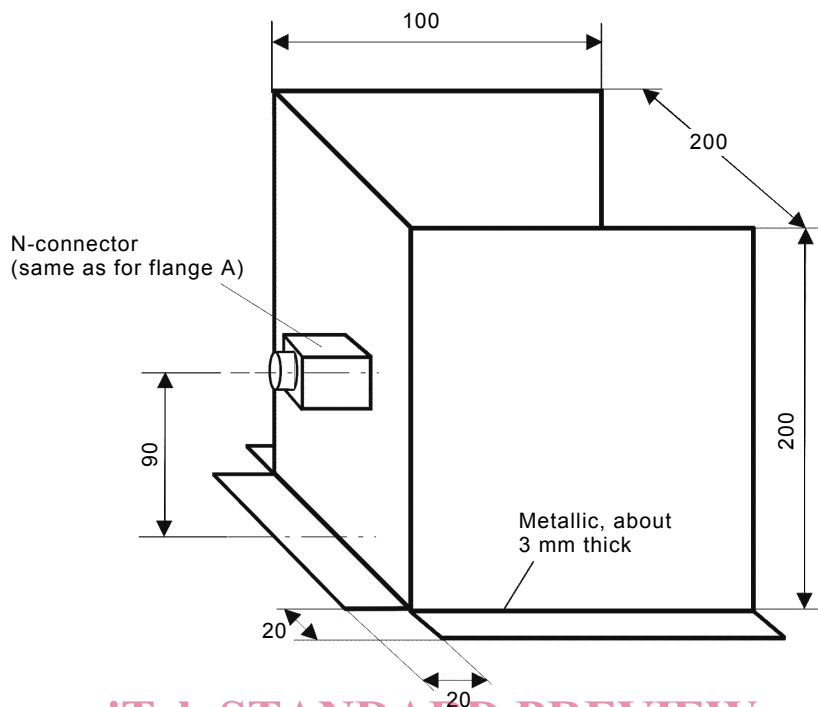


IEC

The bottom sides have to be electrically bonded to the metallic ground plane.

**Figure B.5a – Vertical flange type A (SAD side)**





**iTeh STANDARD PREVIEW**  
 (standards.iteh.ai)

IEC

The bottom sides have to be electrically bonded to the metallic ground plane.

Figure B.5b – Vertical flange type B (clamp EUT side)  
 Figure B.5 – View of the jigs vertical flanges

**Figure B.6 – Test set-up for the reference device calibration method**

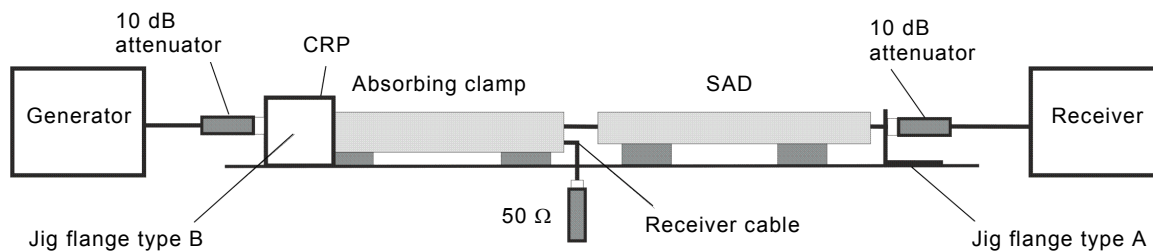
Delete this figure.

**Figure B.7 – Specification of the reference device**

Delete this figure.

**Figure B.8 – Measurement set-up of the decoupling factor *DF***

Replace the existing Figure B.8b (in Corrigendum 1) by the following new figure and title:

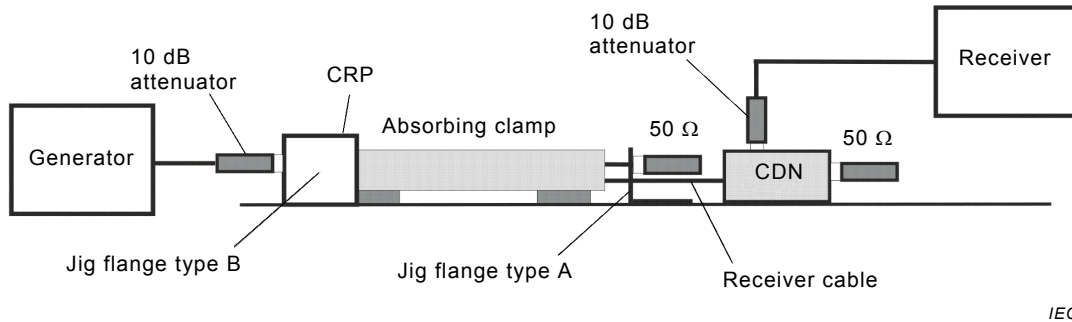


IEC

Figure B.8b – Measurement with the absorbing clamp and SAD placed in the jig

**Figure B.9 – Measurement set-up of the decoupling factor DR**

Replace the existing Figure B.9 by the following new figure:



IEC

**Figure B.9 – Measurement set-up of the decoupling factor DR**

**C.3 Validation measurement procedure**

Add, between the second and third paragraphs of Step 2, the following new paragraph:

**STANDARD PREVIEW**  
standards.iteh.ai

If a CDN is used for measuring the EUT, it should also be used for the ACTS validation (for CDN set-up see B.2.1.1 and Figure B.1).

[CISPR 16-1-3:2004/AMD1:2016](https://standards.iteh.ai/catalog/standards/sist/5c18d183-e3cc-4eb3-961a-1ac5ff102e8/cispr-16-1-3-2004-amd1-2016)

[https://standards.iteh.ai/catalog/standards/sist/5c18d183-e3cc-4eb3-961a-](https://standards.iteh.ai/catalog/standards/sist/5c18d183-e3cc-4eb3-961a-1ac5ff102e8/cispr-16-1-3-2004-amd1-2016)

[1ac5ff102e8/cispr-16-1-3-2004-amd1-2016](https://standards.iteh.ai/catalog/standards/sist/5c18d183-e3cc-4eb3-961a-1ac5ff102e8/cispr-16-1-3-2004-amd1-2016)

**Figure C.1 – Test set-ups for the site attenuation measurement for clamp site validation using the reference device**

In the existing title, delete the phrase “using the reference device”.

Add, after Annex C, the following new bibliography:

**Bibliography**

- [1] Ryser, Heinrich, Uncertainty Contributions to the Clamp Factor CF of the Absorbing Clamp, *Proceedings of 18th International Zurich Symposium on EMC*, Munich 2007.

\_\_\_\_\_

**iTeh STANDARD PREVIEW**  
**(standards.iteh.ai)**

[CISPR 16-1-3:2004/AMD1:2016](https://standards.iteh.ai/catalog/standards/sist/5c18d183-e3cc-4eb3-961a-1aef5ffd02e8/cispr-16-1-3-2004-amd1-2016)

<https://standards.iteh.ai/catalog/standards/sist/5c18d183-e3cc-4eb3-961a-1aef5ffd02e8/cispr-16-1-3-2004-amd1-2016>